

UNT Cleanroom User Fee Schedule*

Release Date August. 18 2017

Resource	Notes	Rates		
		UNT Users	Other University Users	Industrial Users
Cleanroom Access Fee	Each week, enter cleanroom 0 times: no fee; enter >= 1 times: full fee	\$50/week	\$50/week	\$100/week
SEM/EBL	JEOL JSM 7001F w/ XEON patter writer	\$25/Hour	\$25/Hour	\$125/Hour
Photomask Laser Writer	Heidelberg 66	\$30/Hour	\$30/Hour	\$100/Hour
Reactive Ion Etcher-dielectric	AGS RIE MPS-150	\$60/Hour	\$60/Hour	\$100/Hour
Dual Ebeam System Deposition	Nanomaster dual ebeam evaporator	\$20/Hour	\$20/Hour	\$50/Hour
Thermal Evaporator	Denton Vacuum integraty 26	\$15/Hour	\$15/Hour	\$30/Hour
Sputtering & Dual Ebeam	oerlikon Univex 450B	\$20/Hour	\$20/Hour	\$50/Hour
Reactive Ion Etcher-Metal	AGS RIE MPS-150	\$60/Hour	\$60/Hour	\$100/Hour
Organic Thermal Evaporator	Trovato 300C organic deposition system	\$35/Hour	\$35/Hour	\$105/Hour
Chemical Processing Station	Laurell EDC-650Gz-8NPPB processor	N/A	N/A	N/A
Wire Bonder	WestBond 7476 D	&10/Hour	\$10/Hour	\$25/Hour
Ellipsometer	J.A. Woolam Co., Inc. M-2000V Automated Angle Ellipsometer	\$10/Hour	\$10/Hour	\$25/Hour
Spin Coater	Laurell WS-650-23NPP	Included in cleanrom access fee		
Hot Plate	HP 61	Included in cleanrom access fee		
UV Ozone Cleaner	Uvocs	Included in cleanrom access fee		
Fume Hood/Wet Benches	Acid, Base and Solvent	Included in cleanrom access fee		
Staff Training	Tool Training	\$30/Hour	\$30/Hour	\$150/Hour
Staff Assistance	Running Tools, Helping Design, etc	\$30/Hour	\$30/Hour	\$150/Hour

Cleanroom Access & Material Review Contact: Facility Manager: Dr. J.C. Li, jianchao.li@unt.edu, 940-369-5318

Consumables: The facility provides cleanroom garments and personal protective equipment. The facility does not provide consumables such as sputtering targets, evaporation boat & material, photoresist, developer, etc. Any material used in any of the tools will need to be reviewed by cleanroom staff.

Notes: The fee schedule is subject to UNT accounting for further review after interim operational period and will be reevaluated and adjusted.